

General Description

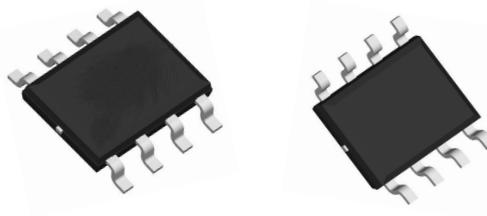
The 6616 uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 1.8V. This device is suitable for use as a load switch.

Product Summary

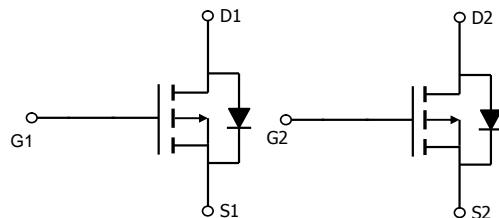
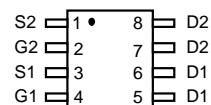
V_{DSS}	$R_{DS(ON)}$ @-4.5V(Typ)	$R_{DS(ON)}$ @-2.5V(Typ)	I_D
-12V	17 mΩ	21mΩ	-16A

- High power and current handling capability
- Lead free product is acquired
- Surface mount package
- PWM applications
- Load switch

SOIC-8



Top View

**Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted**

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	-12	V
Gate-Source Voltage	V_{GS}	± 8	V
Continuous Drain Current ^A	I_D	-16	A
Current ^B		-12	
Pulsed Drain Current ^C	I_{DM}	-105	
Power Dissipation ^B	P_D	3	W
		1.6	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	48	62.5	°C/W
Maximum Junction-to-Ambient ^{A,D}		74	90	°C/W
Maximum Junction-to-Lead	$R_{\theta JL}$	32	40	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-12			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-12\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1 -5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}= \pm 8\text{V}$			± 100	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-0.4	-0.7	-1.0	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=-4.5\text{V}, V_{DS}=-5\text{V}$	-60			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=-4.5\text{V}, I_D=-9\text{A}$ $T_J=125^\circ\text{C}$		17 20	21 25	$\text{m}\Omega$
		$V_{GS}=-2.5\text{V}, I_D=-6.2\text{A}$		21	27	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-9\text{A}$		45		S
V_{SD}	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$		-0.56	-1	V
I_S	Maximum Body-Diode Continuous Current				-3	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-6\text{V}, f=1\text{MHz}$	1390	1740	2100	pF
C_{oss}	Output Capacitance		230	334	435	pF
C_{rss}	Reverse Transfer Capacitance		120	200	280	pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	0.9	1.3	1.7	$\text{k}\Omega$
SWITCHING PARAMETERS						
$Q_g(4.5\text{V})$	Total Gate Charge	$V_{GS}=-4.5\text{V}, V_{DS}=-6\text{V}, I_D=-9\text{A}$	15	19	23	nC
Q_{gs}	Gate Source Charge		3.6	4.5	5.4	nC
Q_{gd}	Gate Drain Charge		3	5.3	7.4	nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=-4.5\text{V}, V_{DS}=-6\text{V}, R_L=0.67\Omega, R_{\text{GEN}}=3\Omega$		240		ns
t_r	Turn-On Rise Time			580		ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			7		μs
t_f	Turn-Off Fall Time			4.2		μs
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-9\text{A}, dI/dt=500\text{A}/\mu\text{s}$	18	22	26	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-9\text{A}, dI/dt=500\text{A}/\mu\text{s}$	14	17	20	nC

A. The value of R_{0JA} is measured with the device mounted on 1in^2 FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using $\leq 10\text{s}$ junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{C}$.

D. The R_{0JA} is the sum of the thermal impedance from junction to lead R_{0UL} and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in^2 FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

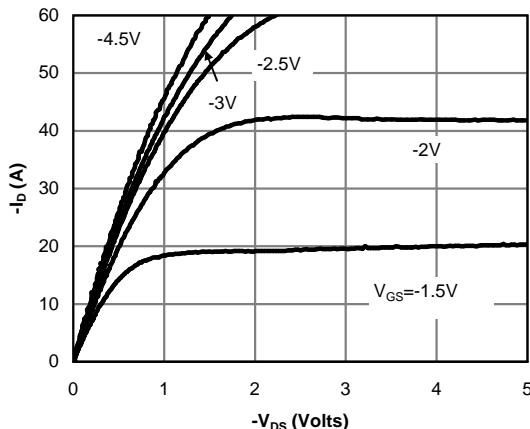


Fig 1: On-Region Characteristics (Note E)

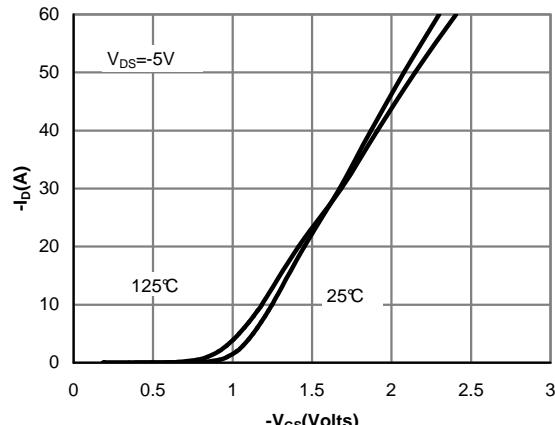


Figure 2: Transfer Characteristics (Note E)

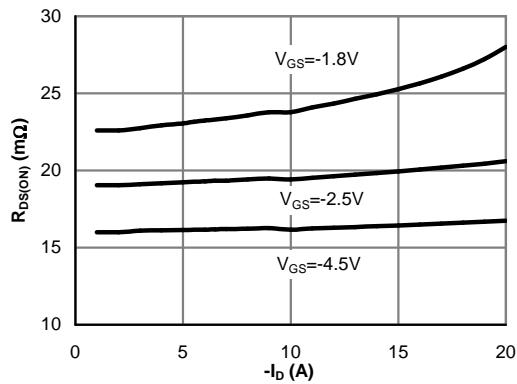


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

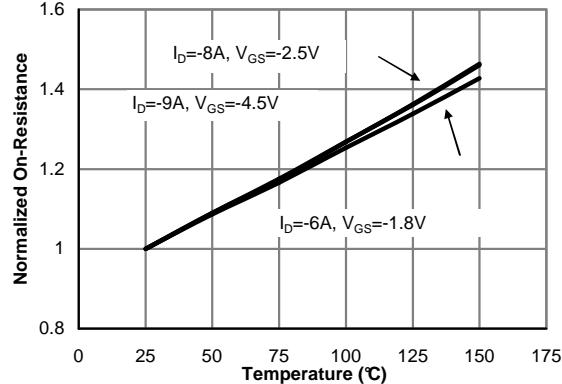


Figure 4: On-Resistance vs. Junction Temperature (Note E)

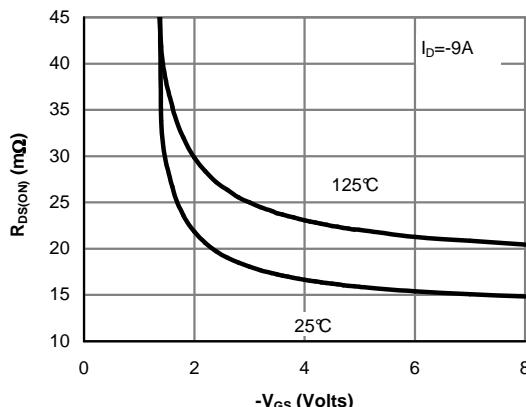


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

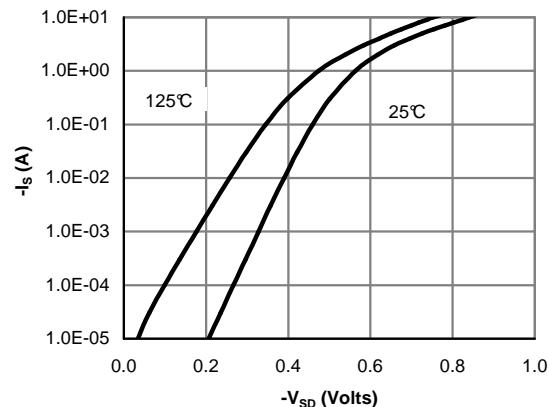
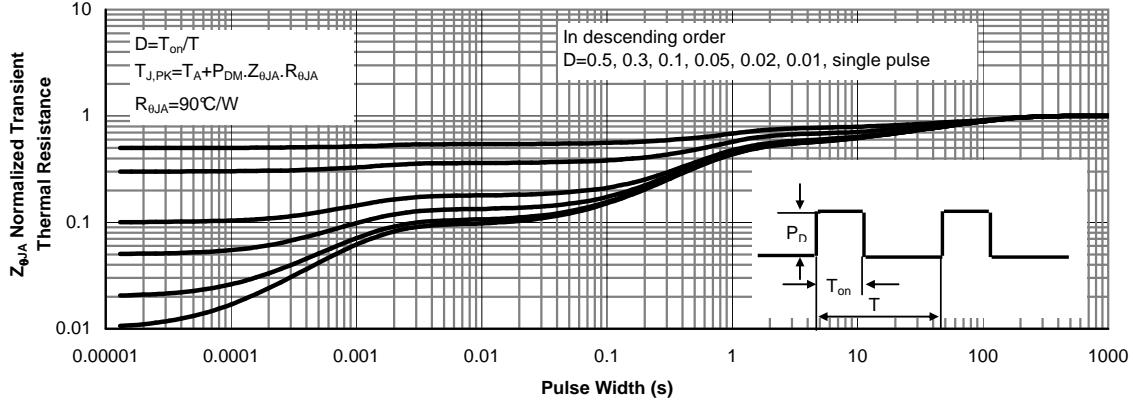
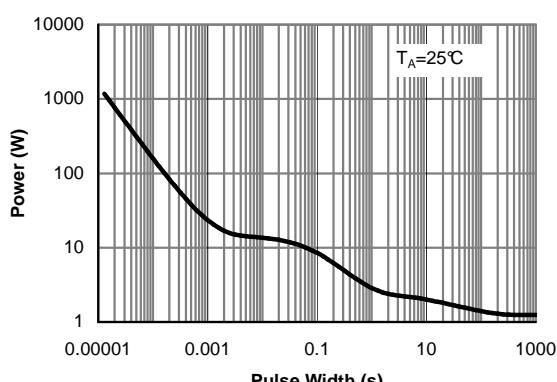
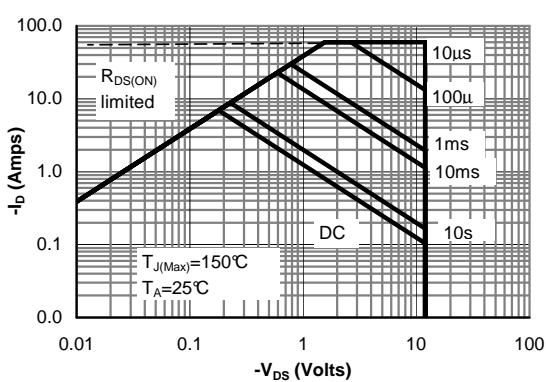
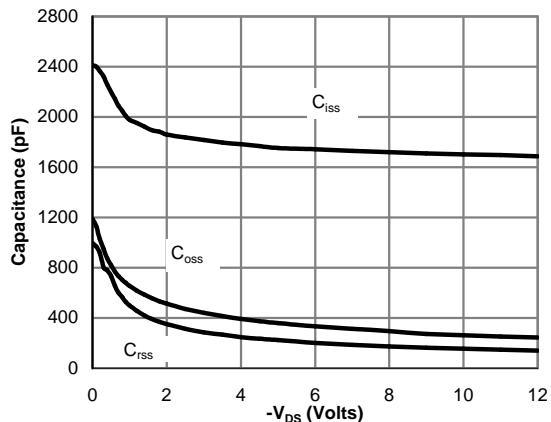
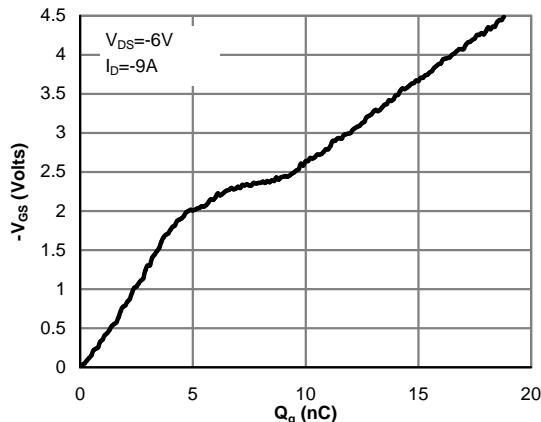
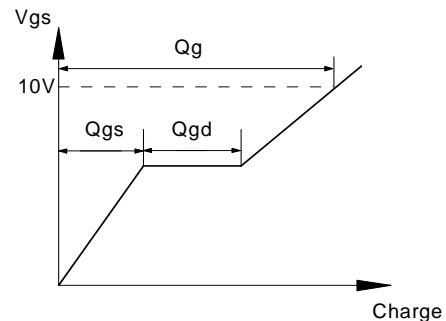
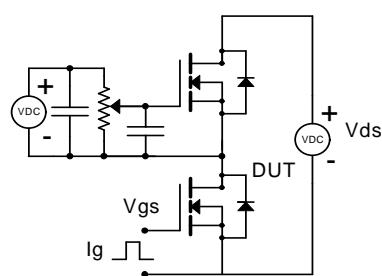


Figure 6: Body-Diode Characteristics (Note E)

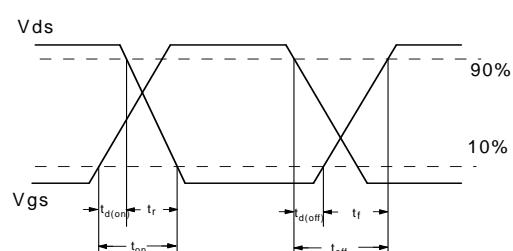
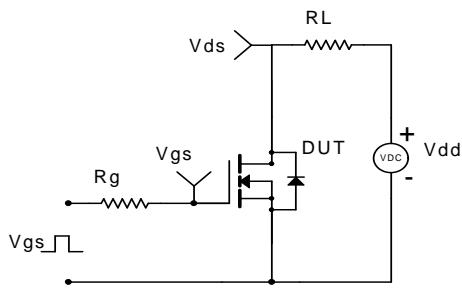
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

